

tg	-40-150		
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(T_j=25 unless otherwise specified)

Symbol	Test Condition	Quadrant	Value		Unit
I _{GT}	V _D =12V R _L =33Ω	- -	MAX.	5	mA
				10	
V _{GT}		ALL	MAX.	1	V
V _{GD}	V _D =V _{DRM} T _j =125 R _L =3.3kΩ	ALL	MIN.	0.2	V
I _L	I _G =1.2I _{GT}	- -	MAX.	15	mA
				20	
I _H	I _T =500mA		MAX.	10	mA
dV/dt	V _D =540V Gate Open T _j =125		MIN.	40	V/μs
(dV/dt) _c	(dI/dt) _c =5A/ms, T _j =110		MIN.	2	V/μs
t _{on}	I _G =20mA I _A =200mA I _R =20mA T _j =25		TYP.	3	

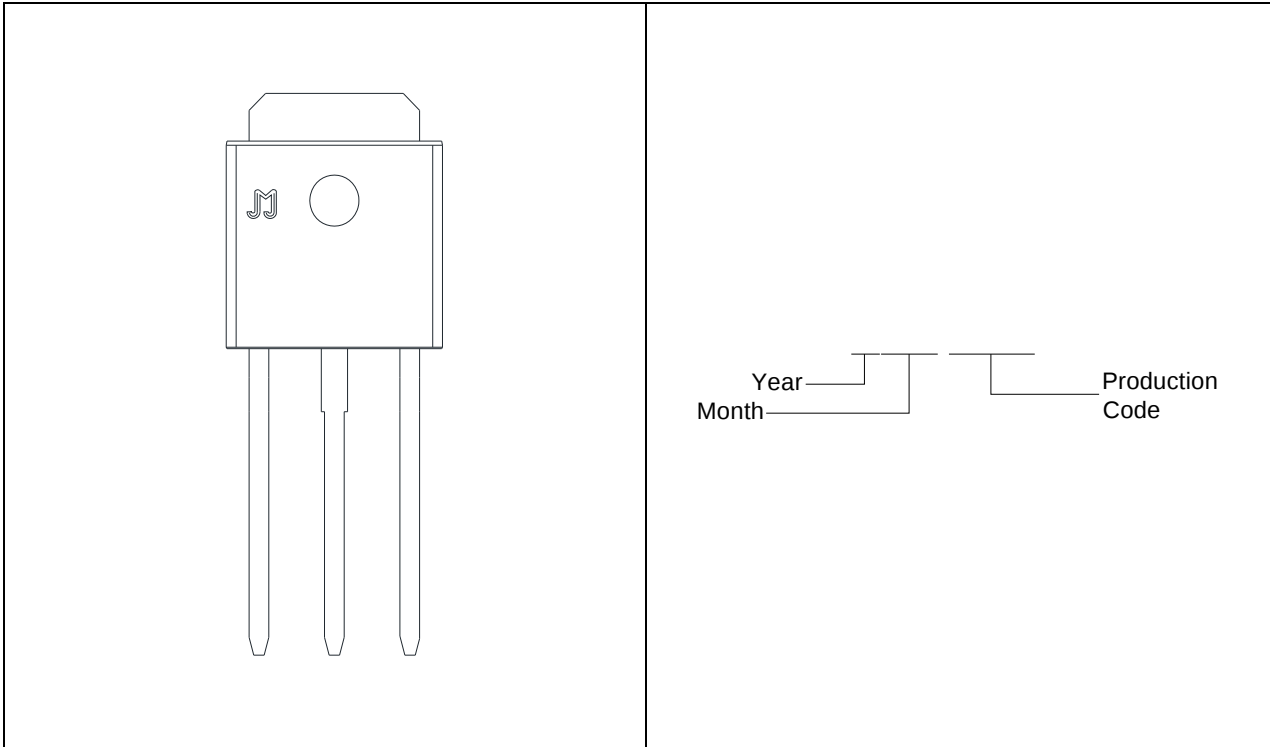
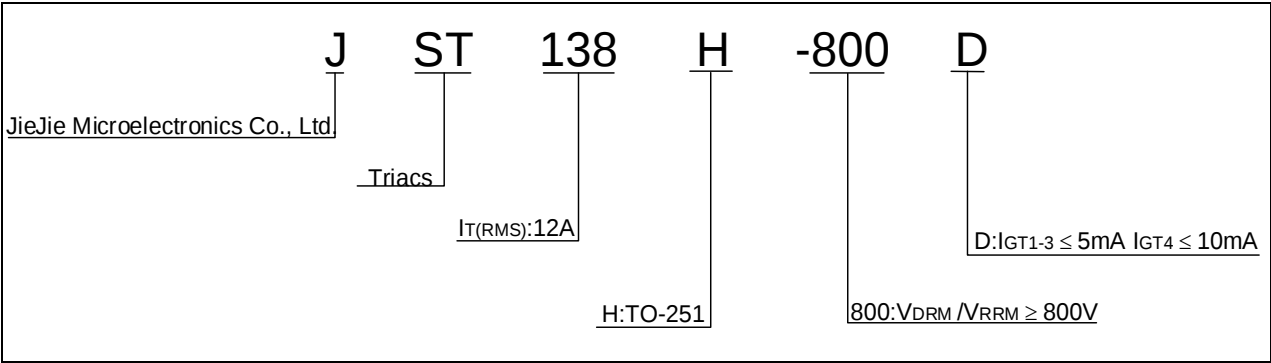
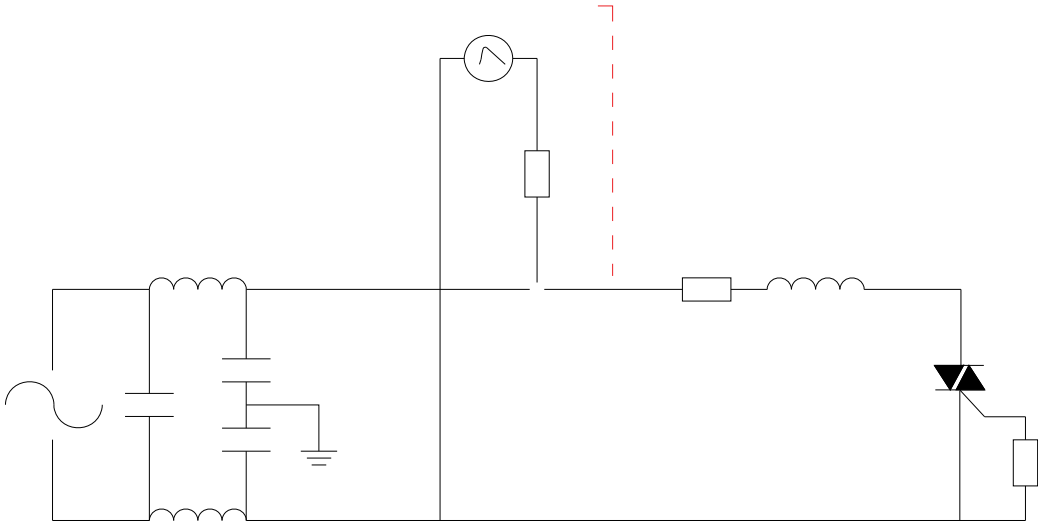


FIG.1:

FIG.7 Test circuit for inductive and resistive loads to IEC-61000-4-5 standards



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